WIREBONDS STATUS

dE				E-front				E-back				Last checked	
strip n.:	1st	2nd	3rd	strip n.:	1st	2nd	3rd	strip n.:	1st	2nd	3rd	date	detector
1				1				1				9/23/07	dE, Ef, Eb
2				2				2					
3				3				3					
4				4				4					
5				5				5					
6				6				6					
7				7				7					
8				8				8					
9				9				9					
10				10				10					
11				11				11					
12				12				12					
13				13				13					
14				14				14					
15				15				15					
16				16				16					
17				17				17					
18				18				18					
19		~		19				19					
20				20				20					
21				21				21					
22				22				22					
23				23				23					
24				24				24					
25				25				25					
26				26				26					
27				27				27					
28				28				28					
29				29				29					
30				30				30					
31				31				31					
32				32				32					

Legend:

X = bond missing / = bond broken ~ = bond damaged

Tel 19

ΔE = 2297-3

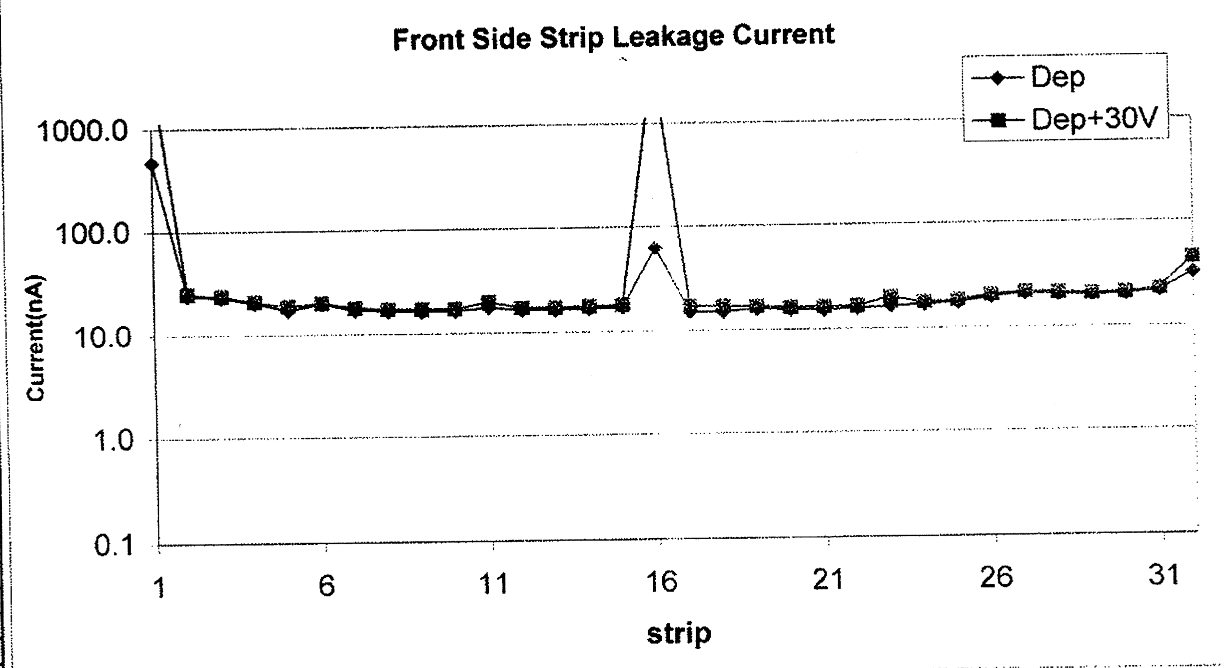
E = 2403-7

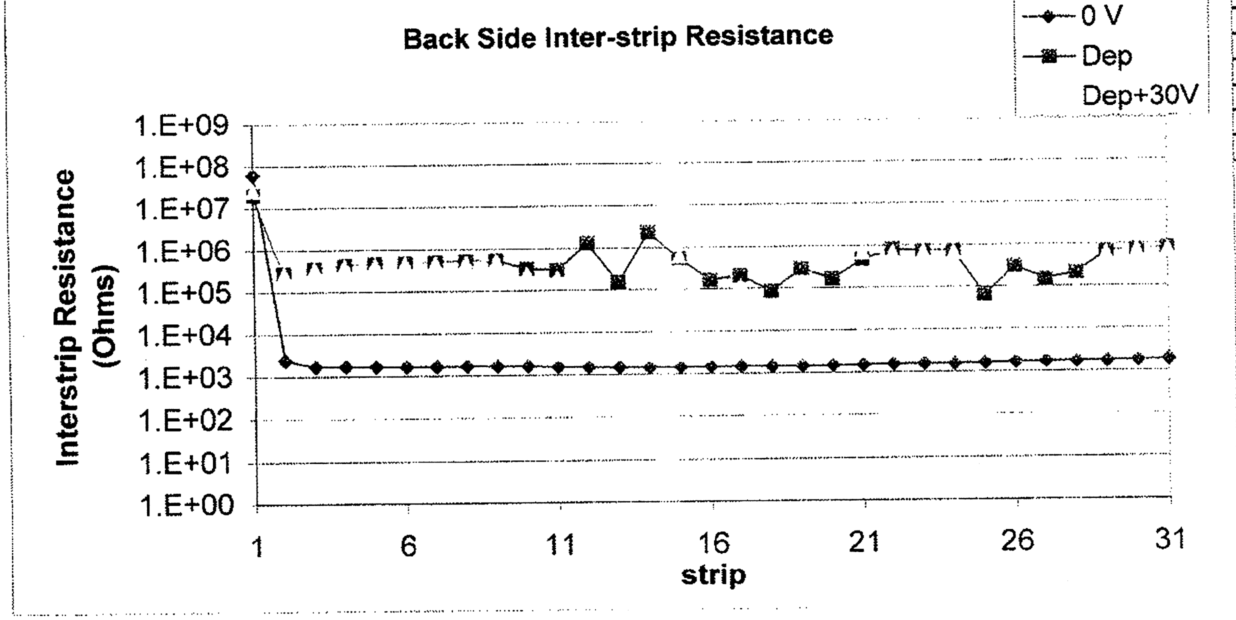
Detector Profile BB7-1500

Wafer No.: 2403-7 **Thickness:** 1541 um **Depletion:** 280 Volts

Front Side Data

Strip	Current(nA) Dep	Dep+30V
1	470.00	4000.00
2	23.70	24.90
3	22.90	23.50
4	20.20	20.90
5	17.10	18.90
6	19.70	20.00
7	16.90	17.80
8	16.50	17.40
9	16.40	17.30
10	16.40	17.30
11	17.40	19.80
12	16.30	17.30
13	16.30	17.30
14	16.60	17.60
15	16.90	17.90
16	62.20	4000.00
17	15.10	17.10
18	15.00	17.00
19	15.80	16.80
20	15.40	16.40
21	15.30	16.30
22	15.60	16.60
23	16.20	19.90
24	16.70	17.60
25	17.30	18.30
26	19.30	20.30
27	20.80	21.80
28	20.20	21.20
29	19.70	20.70
30	20.10	21.00
31	21.60	22.60
32	31.60	44.40
total	1081.20	8595.90





Back Side Data

Strip	Back Resistance (Ω) 0V	Dep	Dep+30V
1	6.2E+07	2.0E+07	2.6E+07
2	2.4E+03	2.8E+05	2.8E+05
3	1.7E+03	3.6E+05	3.6E+05
4	1.7E+03	4.2E+05	4.2E+05
5	1.7E+03	4.6E+05	4.5E+05
6	1.7E+03	4.8E+05	4.7E+05
7	1.7E+03	5.0E+05	4.9E+05
8	1.7E+03	5.2E+05	5.0E+05
9	1.7E+03	5.4E+05	5.2E+05
10	1.6E+03	3.3E+05	2.6E+05
11	1.6E+03	3.1E+05	2.0E+05
12	1.5E+03	1.3E+06	4.9E+05
13	1.5E+03	1.5E+05	5.2E+04
14	1.5E+03	2.3E+06	5.9E+05
15	1.5E+03	5.5E+05	6.2E+05
16	1.5E+03	1.6E+05	6.4E+05
17	1.5E+03	2.0E+05	1.2E+05
18	1.5E+03	8.6E+04	1.8E+04
19	1.5E+03	3.0E+05	1.4E+05
20	1.5E+03	1.7E+05	6.7E+05
21	1.5E+03	4.7E+05	6.9E+05
22	1.5E+03	8.2E+05	6.9E+05
23	1.6E+03	7.3E+05	7.0E+05
24	1.6E+03	7.4E+05	6.8E+05
25	1.6E+03	6.6E+04	2.3E+04
26	1.7E+03	3.1E+05	1.5E+05
27	1.7E+03	1.5E+05	5.1E+04
28	1.7E+03	2.1E+05	9.3E+04
29	1.7E+03	6.7E+05	6.2E+05
30	1.8E+03	7.2E+05	7.2E+05
31	1.8E+03	8.0E+05	7.5E+05

Micron Semiconductor
3/31/05

Resolution Plot HIRA BB7

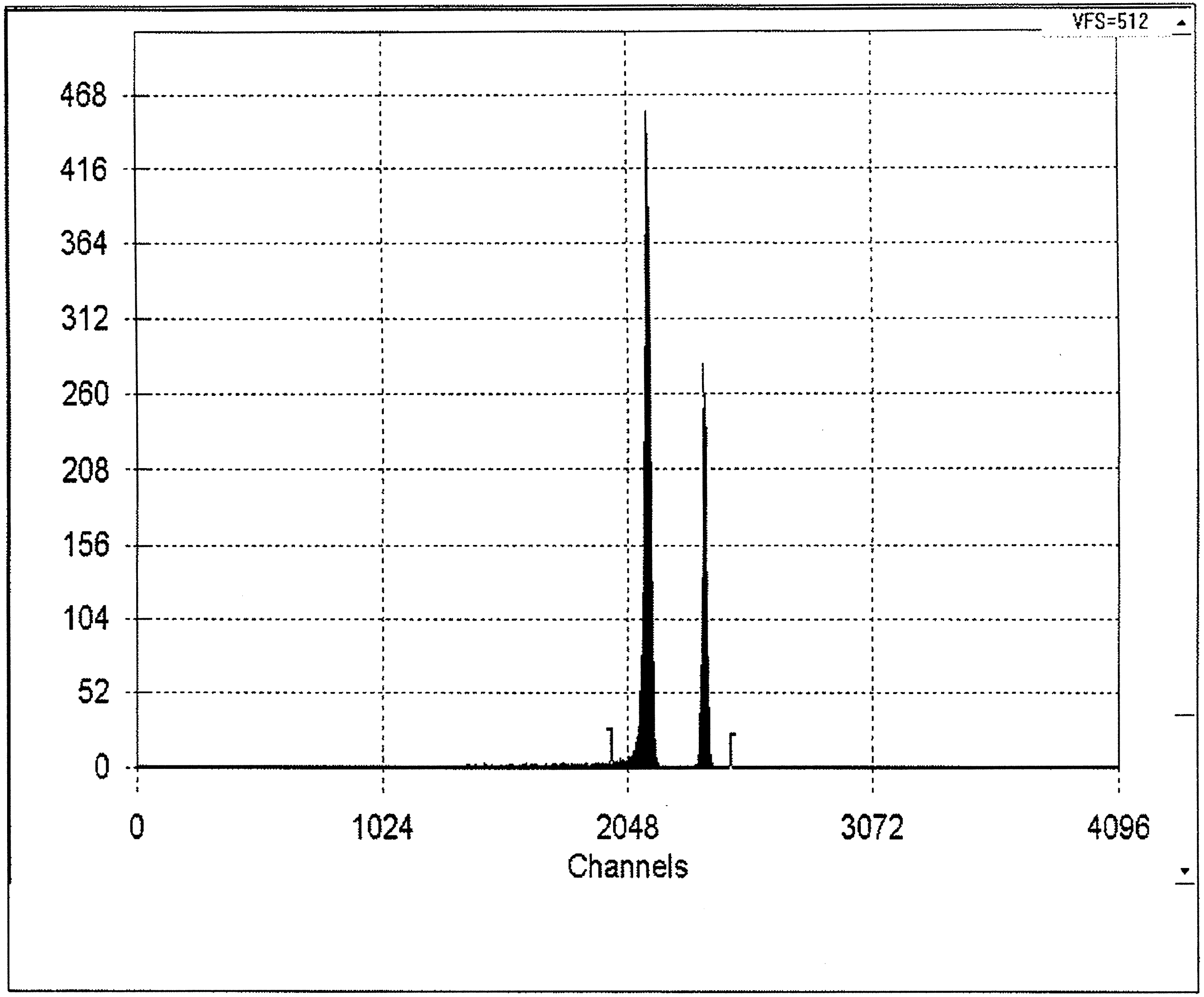
Wafer No.: 2403-7 **Thickness:** 1541 um

JUNCTION

DET LINE: 69.5 KeV
SYSTEM: 48.8 KeV
CAL: 49.5 KeV

OHMIC

DET LINE: 71.9 KeV
SYSTEM: 48.6 KeV
CALC: 52.9 KeV



Source Am 241

Rise Time 1

Flat Top 0

BIAS VOLTS= 300 V **Leakage** 1570 nA

Micron Semiconductor
31/03/2005

Si-detector Inspection Record

Date: 9/23/07 **Time:** ~20:00

Tel n.: 19 **Inspected detector(s):** dE + E(f+b)

1st inspector: Vlad HENZL

2nd inspector: Daniela HENZLOVA

WIREBONDS STATUS

dE				E-front				E-back			
strip n.:	**1st**	**2nd**	**3rd**	**strip n.:**	**1st**	**2nd**	**3rd**	**strip n.:**	**1st**	**2nd**	**3rd**
1				1				1			
2				2				2			
3				3				3			
4				4				4			
5				5				5			
6				6				6			
7				7				7			
8				8				8			
9				9				9			
10				10				10			
11				11				11			
12				12				12			
13				13				13			
14				14				14			
15				15				15			
16				16				16			
17				17				17			
18				18				18			
19		~		19				19			
20				20				20			
21				21				21			
22				22				22			
23				23				23			
24				24				24			
25				25				25			
26				26				26			
27				27				27			
28				28				28			
29				29				29			
30				30				30			
31				31				31			
32				32				32			

Legend:

X = bond missing / = bond broken ~ = bond damaged

Overall detector status:

(e.g. dusty surface, scratches, dirty frame and/or cable, status of telescope can ...)

Ef wirebonds really almost perfect

Eb wirebonds perfect

E=2403-7 | dE=2297-3

Noise tests of detector n.: 2403-7 in telescope n.: 19

		Date	9-12-07	10-25-07	10-31-07	10-31-07						
		electronics	CLASIC	CHIP	CHIP	CHIP						
E back	Chip 0 or shaper 0	chn 0	~5mV	~70mV	42/150	-						
		1	5	52	42	-						
		2	5	~75mV	42/140	-						
		3	5	75	42/170	-						
		4	9mV	70	42/105	-						
		5	7	~55	42/120	-						
		6	6	~75	80/130	-						
		7	5	~100mV	~200mV	-						
		8	10mV	~20	~160mV	-						
		9	5	~70	42/100	-						
		10	7	70	42/120	-						
		11	5	75	42/110	-						
		12	5	~50	~42	-						
		13	10mV	50	42	-						
		14	5	50	42	-						
		15	12mV	50	42	-						
	Chip 1 or shaper 1	chn 0	8mV	~50	42 /42	-						
		1	5	~50	42/160	-						
		2	5	~70	46/310	-						
		3	5	70	42/125	-						
		4	5	70	~110	-						
		5	12mV	70	~150	-						
		6	12mV	~75	~150	-						
		7	5	~75	50/150	-						
		8	6	70	50/260	-						
		9	9mV	75	45/160	-						
		10	6	70	42	-						
		11	7	48	42	-						
		12	16mV	48	42	-						
		13	12mV	48	42	-						
		14	5	48		-						
		15	5	~67mV	42/130	-						
E front	Chip 0 or shaper 2	chn 0	20mV	1050mV	1000mV	800mV						
		1	13mV	210mV	~100	-						
		2	15mV	150mV	50	-						
		3	15mV	150mV	~200mV	40mV						
		4	7	~35	80	-						
		5	7	35	40	-						
		6	7	35	40	-						
		7	7	35	40	-						
		8	10mV	35	40	-						
		9	10mV	500mV	400mV	310mV						
		10	10mV	35	40	-						
		11	14mV	35	40	-						
		12	9	180mV	80mV	-						
		13	20mV	70	55	-						
		14	20mV	50	45	-						
		15	220mV	180mV	140mV	100mV						
	Chip 1 or shaper 3	chn 0	25mV	80	70	-						
		1	7	180mV	120mV	40mV						
		2	13mV	60	45	-						
		3	10mV	50	40	-						
		4	7	50	40	-						
		5	7	50	40	-						
		6	7	50	40	-						
		7	7	50	40	-						
		8	7	50	40	-						
		9	11mV	50	40	-						
		10	8	450mV	630mV	500mV						
		11	15mV	75	40	-						
		12	11mV	180mV	~90mV	-						
		13	11mV	190mV	45	-						
		14	12mV	180mV	40	-						
		15	35mV	700mV	750mV	630mV						

exp 05133
many Ebacks
slowly discharging

bias lowered
by 10V to 290

Si-detector Inspection Record

Date: 10/8/2007 **Time:** 6:30 pm **Tel n.:** 19
Inspected detector(s): dE(2297-3) + EF(2403-7)
What occasion : dE put back in can
1st inspector: Vlad HENZL
2nd inspector: Daniela HENZLOVA

WIREBONDS STATUS

dE					E-front					E-back			
strip n.:	1st	2nd	3rd		strip n.:	1st	2nd	3rd		strip n.:	1st	2nd	3rd
1					1					1			
2					2					2			
3					3					3			
4					4		~	~		4			
5					5					5			
6					6					6			
7					7					7			
8					8					8			
9					9			~		9			
10					10					10			
11					11					11			
12					12					12			
13					13					13			
14		~			14					14			
15					15					15			
16	~				16					16			
17					17					17			
18					18					18			
19	XX				19					19			
20					20			~		20			
21					21					21			
22					22					22			
23					23					23			
24					24					24			
25					25					25			
26					26					26			
27	~				27					27			
28					28					28			
29					29					29			
30					30					30			
31					31					31			
32					32					32			

Legend: XX wirebonds crossed

X = bond missing / = bond broken ~ = bond damaged

Overall detector status:
(e.g. dusty surface, scratches, dirty frame and/or cable, status of telescope can ...)
dE+EF surface cleaned with dry N2

Si-detector Inspection Record

Date: 10/04/07 **Time:** 6:30pm

Tel n.: 19 **Inspected detector(s):** EF+EB

1st inspector: Vladimir Henzl

2nd inspector: Jenny Lee

WIREBONDS STATUS

dE				E-front All okay				E-back → All okay			
strip n.:	1st	2nd	3rd	strip n.:	1st	2nd	3rd	strip n.:	1st	2nd	3rd
1				1				1			
2				2				2			
3				3				3			
4				4				4			
5				5				5			
6				6				6			
7				7				7			
8				8				8			
9				9				9			
10				10				10			
11				11				11			
12				12				12			
13				13				13			
14				14				14			
15				15				15			
16				16				16			
17				17				17			
18				18				18			
19				19				19			
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23				23				23			
24				24				24			
25				25				25			
26				26				26			
27				27				27			
28				28				28			
29				29				29			
30				30				30			
31				31				31			
32				32				32			

Legend:

X = bond missing

/ = bond broken

~ = bond damaged

Overall detector status:

(e.g. dusty surface, scratches, dirty frame and/or cable, status of telescope can ...)